Abstracts

Contrast quantification of millimeter-wave scanning near-field microscope with a slit probe

T. Hamano, F. Watanabe, S. Nuimura, T. Nozokido, J. Bae and K. Mizuno. "Contrast quantification of millimeter-wave scanning near-field microscope with a slit probe." 2000 MTT-S International Microwave Symposium Digest 00.3 (2000 Vol. III [MWSYM]): 1623-1626.

A millimeter-wave scanning near-field (MMW-SNF) microscope with a metal slit-type probe has advantages over a conventional MMW-SNF microscope with a point-type probe. In this paper, contrast of images obtained by the microscope with a slit-type probe has been evaluated in order to quantify the image contrast. The difference of 0.3 in measurement of relative dielectric constants of objects can be distinguished when the dielectric constants are less than 8.0.

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